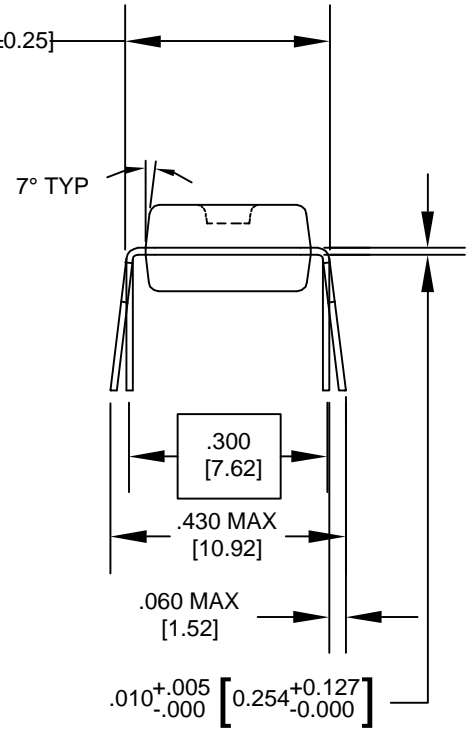
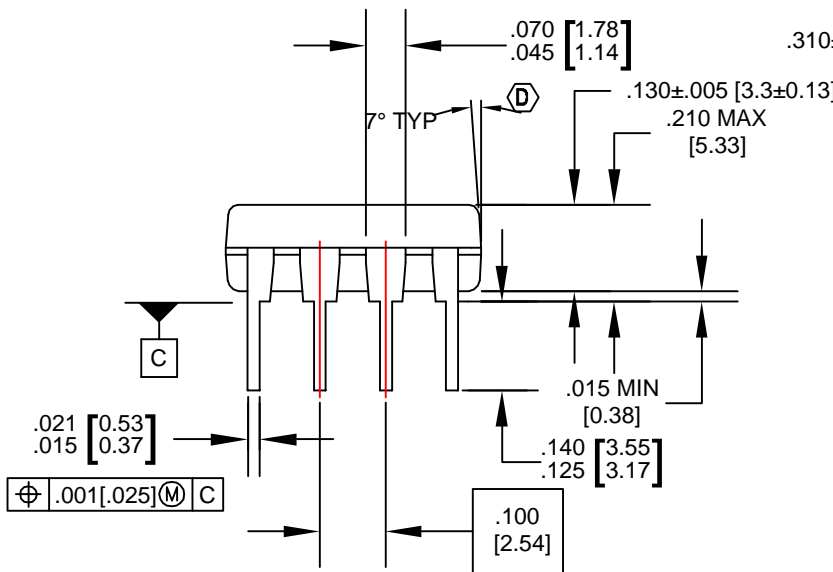
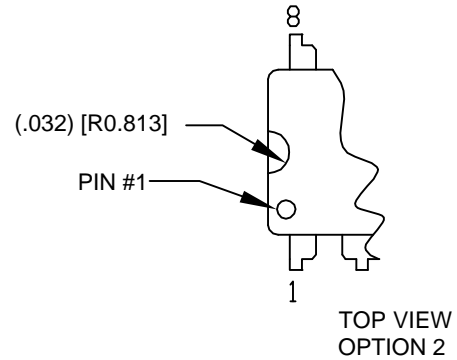
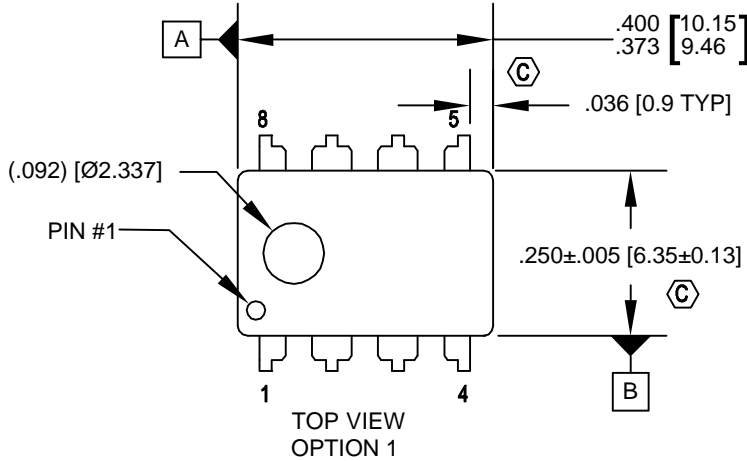


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REVISIONS			
LTR	DESCRIPTION	ECN	DATE
G	Redraw original CAD file lost	ECN-MKT-N08EREVG	02-21-2006
			J.KINGSBURY



**NOTES:**

- A. CONFORMS TO JEDEC REGISTRATION MS-001, VARIATIONS BA
- B. CONTROLLING DIMENSIONS ARE IN INCHES  
REFERENCE DIMENSIONS ARE IN MILLIMETERS
- C. DOES NOT INCLUDE MOLD FLASH OR PROTRUSIONS.  
MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED .010 INCHES OR 0.25MM.
- D. DOES NOT INCLUDE DAMBAR PROTRUSIONS.  
DAMBAR PROTRUSIONS SHALL NOT EXCEED .010 INCHES OR 0.25MM.
- E. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

N08EREVG

APPROVALS	DATE	 Bayan Lepas, FIZ, 11900, Penang, Malaysia.
DRAWN J KINGSBURY	02-17-2006	
DFTG. CHK H ALLEN	02-21-2006	
ENGR. CHK H ALLEN	02-21-2006	
PROJECTION		8LD, PDIP, JEDEC MS-001, .300" WIDE
SCALE N/A	SIZE N/A	DRAWING NUMBER MKT-N08E
DD	NOT SCALE DRAWING	REV G
		SHEET 1 of 1